

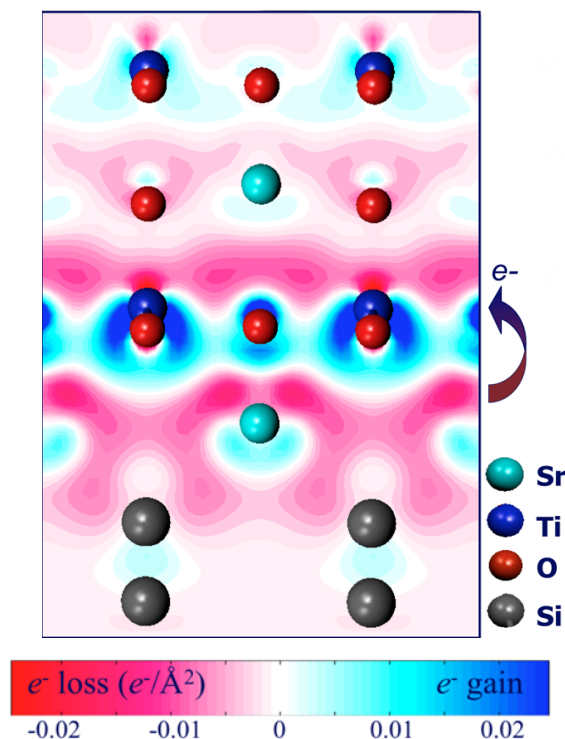
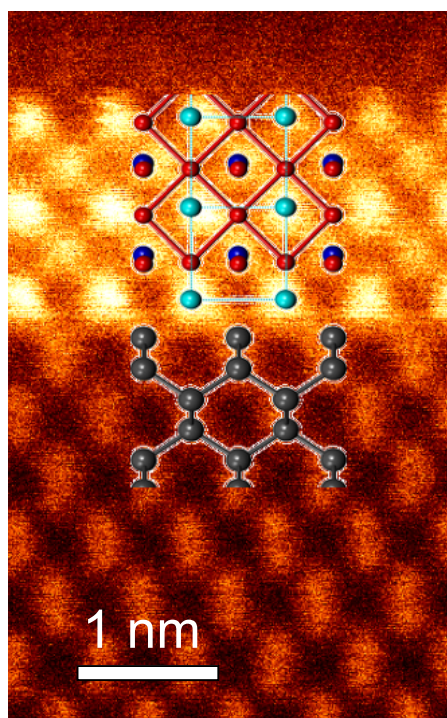
Impact of interfacial bonding on oxide functionality



Transition metal oxides exhibit many properties that can be harnessed in novel devices. For example, an epitaxial ferroelectric on silicon enables a nonvolatile transistor that remembers its state without continuous power consumption. A critical question is how the oxide/silicon interface affects the oxide functionality.

TEM image of the epitaxial SrTiO_3/Si interface.

Superimposed is the predicted structure from first principles theory, showing excellent agreement.



Theory shows that the interfacial bonding is ionic: electrons transfer from the silicon to the oxide.

The positive Si layer then pushes the Ti cations away and pins the oxide polarization.

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